

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-02
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1. Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Consumer / Commercial / Industrial (JESD 47) and Automotive / Military accelerated environment reliability stress tests (Including: Pre-condition / MSL / Accelerated Temperature-Humidity test / Temperature-Humidity with bias test / Temperature Cycling test / Power and temperature cycling / Temperature storage test / Salt)	J-STD-020, JESD22-A101/A102/A106/A107/A110/A113/ A118/A119; IEC-60068-2-1/2/3/14/ 38/52, MIL-STD-202/750/810/883, JESD JEP001; EIA-364-32, EIAJ ED-4701, AEC-Q200-004; AEC-Q005/Q006,	Or customer specified test
Consumer/ Commercial / Industrial (JESD 47) and Automotive / Military accelerated lifetime simulation tests. (Including: Temperature, Bias, and Operating Life test / early life failure rate / Endurance and Data retention test / Short circuit / Miscellaneous test)	JESD22-A108/A117, MIL-STD-202/750/810/883, AEC-Q100-005/008/012, AEC-Q101-004/006, Customer standards	Or customer specified test

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